

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/601,582	LIU ET AL.
	Examiner	Art Unit
	Claire M. Kaufman	1646

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
435	69.1,320.1, 325,252.3 253.11	2/27/2006	CLL
530	350,402		
536	23.1,23.5		
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